

INTRODUCING THE ILS-W2

INLINE WAFER ELECTRICAL QUALITY INSPECTION



THE ULTIMATE WAFER ELECTRICAL QUALITY INSPECTION UNIT FOR WAFER INSPECTION SYSTEMS (WIS) FOR

- **WAFER LINES**
- **CELL LINES**

MEASUREMENT TECHNIQUE - INLINE PHOTOLUMINESCENCE IMAGING

WAFER TYPES

- **STANDARD MULTI**
- **CAST-MONO**
- **HP MULTI**
- **CZ MONO**

FULL WIS LINE SPEED – UP TO 4800 WPH

A RANGE OF AUTOMATION OPTIONS

- **INTEGRATED WITH THE BT IMAGING QS-W2 WIS**
- **OFFLINE AUTOMATED PILOT SCALE OPTIONS**
- **INTEGRATED WITH EXISTING WIS USING BT IMAGING IQ UNIT**

THE ONLY INLINE PHOTOLUMINESCENCE IMAGING UNIT BACKED BY BT IMAGING'S EXTENSIVE PATENT PORTFOLIO

INTEGRATED WAFER INSPECTION AND SORTING SOFTWARE

- **REJECTS LOW EFFICIENCY WAFERS**
- **SORTS GOOD WAFERS INTO EFFICIENCY BINS**
- **ALGORITHMS OPTIMIZED FOR EACH WAFER TYPE**
- **ALGORITHMS INTEGRATED WITH OTHER WIS MEASUREMENTS IF AVAILABLE**
- **USER-ADJUSTABLE SETTINGS TO ALLOW FOR DIFFERENT USE CASES**
- **HIGH-VALUE CELL LINE CALIBRATION METHODS BUILT-IN**
- **EASY TO USE GRAPHICAL USER INTERFACE**

TYPICAL USE CASES

- **WAFER REJECTION**
- **GOOD WAFER SORTING BY EFFICIENCY**
- **WAFER AND CELL R&D, LINE PROCESS IMPROVEMENT AND DEBUG**